1. Record Nr.	UNINA9910451262803321
Titolo	The youth labor market problem [[electronic resource]] : its nature, causes, and consequences / / edited by Ricard B. Freeman and David A. Wise
Pubbl/distr/stampa	Chicago, : University of Chicago Press, 1982
ISBN	1-281-22344-1 9786611223441 0-226-26186-7
Descrizione fisica	1 online resource (568 p.)
Collana	A National Bureau of Economic Research conference report
Altri autori (Persone)	FreemanRichard B <1943-> (Richard Barry) WiseDavid A
Disciplina	331.3/412 331.3412
Soggetti	Working class Youth - Employment Electronic books.
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographies and indexes.
Nota di contenuto	Front matter -- Contents -- 1. The Youth Labor Market Problem: Its Nature Causes and Consequences -- 2. Teenage Unemployment: What is the Problem? -- 3. The Youth Labor Market Problem in the United States: An Overview -- 4. Why Does the Rate of Youth Labor Force Activity Differ across Surveys? -- 5. Economic Determinants of Geographic and Individual Variation in the Labor Market Position of Young Persons -- 6. Time Series Changes in Youth Joblessness -- 7. The Dynamics of Youth Unemployment -- 8. Labor Turnover and Youth Unemployment -- 9. High School Preparation and Early Labor Force Experience -- 10. Teenage Unemployment: Permanent Scars or Temporary Blemishes? -- 1.1 The Employment and Wage Consequences of Teenage Women's Nonemployment -- 12. Dead-end Jobs and Youth Unemployment -- 13. Family Effects in Youth Employment -- 14. The Minimum Wage and Job Turnover in Markets for Young Workers -- 15. Youth Unemployment in Britain and the United States Compared -- Contributors -- Author Index -- Subject

	Index
Sommario/riassunto	This volume brings together a massive body of much-needed research information on a problem of crucial importance to labor economists, policy makers, and society in general: unemployment among the young. The thirteen studies detail the ambiguity and inadequacy of our present standard statistics as applied to youth employment, point out the error in many commonly accepted views, and show that many critically important aspects of this problem are not adequately understood. These studies also supply a significant amount of raw data, furnish a platform for further research and theoretical work in labor economics, and direct attention to promising avenues for future programs.

2.	Record Nr.	UNINA9910454319803321
	Titolo	Radiation effects and soft errors in integrated circuits and electronic devices [[electronic resource] /] / editors, R.D. Schrimpf, D.M. Fleetwood
	Pubbl/distr/stampa	Singapore ; ; New Jersey, : World Scientific Pub., c2004
	ISBN	1-281-93459-3 9786611934590 981-279-470-0
	Descrizione fisica	1 online resource (349 p.)
	Collana	Selected topics in electronics and systems ; ; vol. 34
	Altri autori (Persone)	SchrimpfRonald Donald FleetwoodD. M (Dan M.)
	Disciplina	621.3815
	Soggetti	Electronic circuits - Effect of radiation on Integrated circuits - Effect of radiation on Electronic books.
	Lingua di pubblicazione	Inglese
	Formato	Materiale a stampa
	Livello bibliografico	Monografia
	Note generali	Also published in the International Journal of High Speed Electronics and Systems, v. 14, no. 2 (2004) p. 285-623.
	Nota di bibliografia	Includes bibliographical references.
	Nota di contenuto	CONTENTS ; Preface ; Single Event Effects in Avionics and on the Ground ; 1.

Sommario/riassunto

This book provides a detailed treatment of radiation effects in electronic devices, including effects at the material, device, and circuit levels. The emphasis is on transient effects caused by single ionizing particles (single-event effects and soft errors) and effects produced by the cumulative energy deposited by the radiation (total ionizing dose effects). Bipolar (Si and SiGe), metal-oxide-semiconductor (MOS), and compound semiconductor technologies are discussed. In addition to considering the specific issues associated with high-performance devices and technologies, the book includes t